	Kevin S. Orwig	4161		
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Notice of References Cited	10/593,242	Reexamination KAMIYAMA ET AL.		
	Application/Control No. Applicant(s)/Patent Und		nt Under	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0110433 A1	05-2006	Terahara et al.	424/448
	В	US-			
	U	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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